

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10589049	URTEL ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Loewe, Sun Jae Y	1626

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
keyword search in file CAPLUS in STN; search in file	12/17/2008	KP
keyword search in EAST (USPGPUB, USPAT, EPO, JPO, DERWENT, USOCR, FPRS); search in file	12/17/2008	KP
interference search in EAST (USPGPUB and USPAT)	12/17/2008	KP

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
568	852	12/17/2008	KP
562	512	12/17/2008	KP

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